International TOR Rectifier

HEXFET® TRANSISTOR

IRFI260

N-CHANNEL

200 Volt, 0.060Ω, HEXFET

HEXFET technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry design achieves very low on-state resistance combined with high transconductance.

HEXFET transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching, ease of paralleling and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, high energy pulse circuits and virtually any application where high reliability is required.

The HEXFET transistor's totally isolated package eliminates the need for additional isolating material between the device and the heatsink. This improves thermal efficiency and reduces drain capacitance.

Product Summary

Part Number	BVDSS	RDS(on)	lD
IRFI260	200V	0.060Ω	45A*

Features:

- Hermetically Sealed
- Electrically Isolated
- Simple Drive Requirements
- Ease of Paralleling
- Ceramic Eyelets

Absolute Maximum Ratings

	Parameter	IRFI260	Units
ID @ VGS = 10V, TC = 25°C	Continuous Drain Current	45*	
ID @ VGS = 10V, TC = 100°C	Continuous Drain Current	29	Α
IDM	Pulsed Drain Current ①	180	
P _D @ T _C = 25°C	Max. Power Dissipation	300	W
	Linear Derating Factor	2.4	W/K ⑤
VGS	Gate-to-Source Voltage	±20	V
EAS	Single Pulse Avalanche Energy ②	700	mJ
IAR	Avalanche Current ①	45	Α
EAR	Repetitive Avalanche Energy ①	30	mJ
dv/dt	Peak Diode Recovery dv/dt 3	4.3	V/ns
TJ	Operating Junction	-55 to 150	
TSTG	Storage Temperature Range		°C
	Lead Temperature 300 (0.063	in. (1.6mm) from case for 10 sec.)	
	Weight	10.9 (typical)	g

^{*} In current limited by pin diameter

IRFI260 Device

Electrical Characteristics @ Tj = 25°C (Unless Otherwise Specified)

Parameter		Min.	Тур.	Max.	Units	Test Cor	ditions	
BVDSS	Drain-to-Source Breakdown Voltage	200		_	V	VGS = 0V, I) = 1.0 mA	
ΔBVDSS/ΔTJ	Temp. Coefficient of Breakdown Voltage	_	0.24	_	V/°C	Reference to 25°C, ID = 1.0 mA		
RDS(on)	Static Drain-to-Source	_	I	0.060		VGS = 10V, ID =29A ④		
	On-State Resistance	_	_	0.068	Ω	VGS = 10V	VGS = 10V, ID = 45A	
VGS(th)	Gate Threshold Voltage	2.0		4.0	V	V _{DS} = V _{GS} ,	I _D = 250μA	
9fs	Forward Transconductance	22		_	S (汉)	V _{DS} ≥ 15V, I _I	os = 29A @	
IDSS	Zero Gate Voltage Drain Current		I	25	μA	V _{DS} =0.8 x Max	0. 00	
		_		250		V _{DS} = 0.8 x	Max Rating	
						VGS = 0V, 1	J = 125°C	
IGSS	Gate-to-Source Leakage Forward	_		100	nA	VGS =	: 20V	
IGSS	Gate-to-Source Leakage Reverse	_	_	-100		VGS =	-20V	
Qg	Total Gate Charge	_		230		VGS =10V, ID = 45A		
Qgs	Gate-to-Source Charge	_		40	nC	V _{DS} = Max. Rating x 0.5		
Q_{gd}	Gate-to-Drain ("Miller") Charge	_	_	110				
td(on)	Turn-On Delay Time	_		29		V _{DD} = 100\	/, I _D =45A,	
tr	Rise Time	_		120	ns	$R_G = 2.35\Omega$,	Vgs =10V	
td(off)	Turn-Off Delay Time	_	_	110				
tf	FallTime	_		92				
LD	Internal Drain Inductance	_	8.7	_		Measured from the drain lead, 6mm (0.25 in.) from package to center of die.	Modified MOSFET symbol showing the internal inductances.	
LS	Internal Source Inductance	_	8.7	_	nH	Measured from the source lead, 6mm (0.25 in.) from package to source bonding pad.		
Ciss	Input Capacitance	_	5100	_		VGS = 0V, VDS = 25V		
Coss	Output Capacitance	_	1100	_	pF	f = 1.0 MHz		
C _{rss}	Reverse Transfer Capacitance	_	280	_				

Source-Drain Diode Ratings and Characteristics

Parameter		Min.	Тур.	Max.	Units	Test Conditions
Is	Continuous Source Current (Body Diode)		_	45*		Modified MOSFET symbol showing the
ISM	Pulse Source Current (Body Diode) ①		_	180	Α	integral reverse p-n junction rectifier.
VSD	Diode Forward Voltage		_	1.8	V	$T_j = 25$ °C, $I_S = 45$ A, $V_{GS} = 0$ V ④
trr	Reverse Recovery Time		_	420	ns	$T_j = 25^{\circ}C$, $I_F = 45A$, $di/dt \le 100A/\mu s$
QRR	RR Reverse Recovery Charge		_	4.9	μС	V _{DD} ≤ 50V ④
ton	Forward Turn-On Time Intrinsic tur	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by LS + LD.				

Thermal Resistance

	Parameter	Min.	Тур.	Max.	Units	Test Conditions
RthJC	Junction-to-Case		_	0.42		
R _{th} JA	Junction-to-Ambient		_	30	K/W ⑤	typical socket mount
RthCS	Case-to-Sink	_	0.21	_		mounting surface flat, smooth

⑤ K/W = °C/W W/K = W/°C

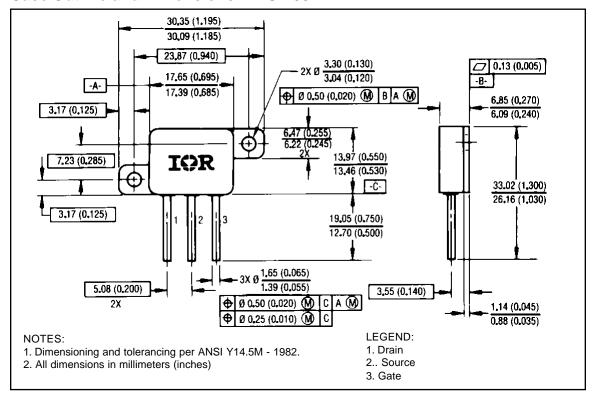
① Repetitive Rating; Pulse width limited by maximum junction temperature.

② @ V_{DD} = 50V, Starting T_J = 25°C, E_{AS} = [0.5 * L * (I_{L}^{2}) * [BV_{DSS}/(BV_{DSS}-V_{DD})] Peak I_L = 45A, V_{GS} = 10V, 25 ≤ R_G ≤ 200Ω

③ ISD \leq 45A, di/dt \leq 130 A/ μ s, VDD \leq BVDSS, TJ \leq 150°C Suggested RG = 2.35 Ω

 $[\]textcircled{4}$ Pulse width $\leq 300 \ \mu s$; Duty Cycle $\leq 2\%$

Case Outline and Dimensions —TO-259AA



CAUTION BERYLLIA WARNING PER MIL-PRF-19500

Packages containing beryllia shall not be ground, sandblasted, machined, or have other operations performed on them which will produce beryllia or beryllium dust. Furthermore, beryllium oxides packages shall not be placed in acids that will produce fumes containing beryllium.

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